SCAS024A - JUNE 1987 - REVISED APRIL 1993

- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin V_{CC} and GND Configuration Minimizes High-Speed Switching Noise
- EPIC[™] (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs



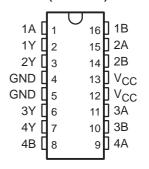
These devices contain four independent 2-input NOR gates. They perform the Boolean functions $Y = \overline{A} \cdot \overline{B}$ or $Y = \overline{A} + \overline{B}$ in positive logic.

The 54AC11002 is characterized for operation over the full military temperature range of -55°C to 125°C. The 74AC11002 is characterized for operation from -40°C to 85°C.

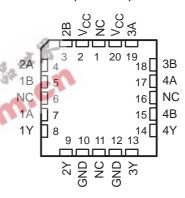
FUNCTION TABLE (each gate)

	INP	UTS	OUTPUT
	Α	В	Y
Ī	Н	X	. [
ı	Χ	Н	L
	L	L	Н

54AC11002 . . . J PACKAGE 74AC11002 . . . D OR N PACKAGE (TOP VIEW)

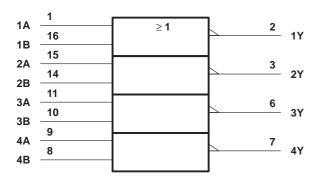


54AC11002...FK PACKAGE (TOP VIEW)



NC - No internal connection

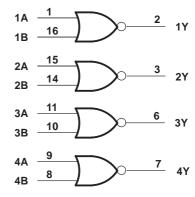
logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, and N packages.

logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, V _O (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, $I_{ K }(V_1 < 0 \text{ or } V_1 > V_{CC})$	±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±50 mA
Continuous output current, I _O (V _O = 0 to V _{CC})	±50 mA
Continuous current through V _{CC} or GND	±100 mA
Storage temperature range	65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

			54AC11002			74AC11002			UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
Vcc	Supply voltage		3	5	5.5	3	5	5.5	V	
		V _{CC} = 3 V	2.1	d /™	*	2.1				
V_{IH}	High-level input voltage	V _{CC} = 4.5 V	3.15			3.15			V	
		$V_{CC} = 5.5 \text{ V}$	3.85			3.85				
V _{IL}	Low-level input voltage	VCC = 3 V	200		0.9			0.9		
		V _{CC} = 4.5 V			1.35			1.35	V	
		V _{CC} = 5.5 V			1.65			1.65		
٧ _I	Input voltage		0		VCC	0		VCC	V	
VO	Output voltage		0		VCC	0		VCC	V	
	High-level output c <mark>urrent</mark>	V _{CC} = 3 V			-4			-4		
ІОН		$V_{CC} = 4.5 \text{ V}$			-24			-24	mA	
		V _{CC} = 5.5 V			-24			-24		
	Low-level output current	V _{CC} = 3 V			12			12		
I _{OL}		V _{CC} = 4.5 V			24			24	mA	
		V _{CC} = 5.5 V			24			24		
Δt/Δν	Input transition rise or fall rate		0		10	0		10	ns/V	
TA	Operating free-air temperature		-55		125	-40		85	°C	

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Vaa	T,	Վ = 25°C	;	54AC1	1002	74AC11002		UNIT
PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	ONIT
	I _{OH} = – 50 μA	3 V	2.9			2.9		2.9		
		4.5 V	4.4			4.4		4.4		
		5.5 V	5.4			5.4		5.4		
Vou	I _{OH} = -4 mA	3 V	2.58			2.4		2.48		\/
VOH		4.5 V	3.94			3.7		3.8		V
	I _{OH} = - 24 mA	5.5 V	4.94			4.7		4.8		
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V				3.85				
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V						3.85		
	I _{OL} = 50 μA	3 V			0.1		0.1		0.1	
		4.5 V			0.1		0.1		0.1	
		5.5 V			0.1		0.1		0.1	
VOL	I _{OL} = 12 mA	3 V			0.36		0.5		0.44	V
VOL.	I _{OL} = 24 mA	4.5 V			0.36		0.5		0.44	v
	IOL = 24 IIIA	5.5 V	3	. 40	0.36		0.5		0.44	
	I _{OL} = 50 mA [†]	5.5 V	23	\$.	C	1	1.65			
	I _{OL} = 75 mA [†]	5.5 V		-0	1				1.65	
lį	V _I = V _{CC} or GND	5. 5 V		3,,,	±0.1		±1		±1	μΑ
ICC	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		80		40	μΑ
C _i	$V_I = V_{CC}$ or GND	5 V		3.5						pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T _A = 25°C			54AC	11002	74AC11002		UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
^t PLH	A or B	Y	1.5	7	8.6	1.5	10.7	1.5	9.9	no
^t PHL	AOIB		1.5	6	7.5	1.5	9	1.5	8.4	ns

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	T _A = 25°C			54AC11002		74AC11002		UNIT
PARAMETER			MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
^t PLH	A or P	V	1.5	4.5	6.1	1.5	7.4	1.5	6.9	no
^t PHL	A or B	ī	1.5	4	5.7	1.5	6.8	1.5	6.4	ns

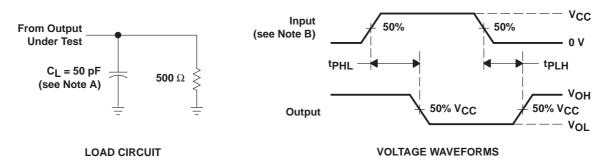
operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER		TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per gate	$C_L = 50 \text{ pF}, f = 1 \text{ MHz}$	32	pF



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PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \ \Omega$, $t_f = 3 \ ns$, $t_f = 3 \ ns$.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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